

**Notice of References Cited**

Application/Control No.

10/568,022

Applicant(s)/Patent Under  
Reexamination  
LEE ET AL.

Examiner

/Susan W. Berman/

Art Unit

1796

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2006/0207644	09-2006	Robinson et al.	136/243
*	B	US-2008/0118658	05-2008	Kato et al.	427/508
*	C	US-4,623,594	11-1986	Keough, Allen H.	428/500
*	D	US-7,323,232	01-2008	Takeda et al.	428/1.55
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
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